

<b>Notice of References Cited</b>	Application/Control No. 09/985,689	Applicant(s)/Patent Under Reexamination HATADA ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tobe et al, 1997 EMBL Acc# .E03808 Alignment with SID NO: 1.
	V	Christianson et al, 1998 from WO9856927. Alignment with SID NO: 1.
	W	Hitomi et al, 1999 from WO9918218. Alignment with SEQ ID NO: 1.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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